

SIXTEENTH ANNUAL

BiTS™

Burn-in & Test Strategies Workshop

March 15 - 18, 2015

Hilton Phoenix / Mesa Hotel
Mesa, Arizona



Archive – Session 5

Session 5

Ashok Kabadi
Session Chair

BiTS Workshop 2015 Schedule

Performance Day

Tuesday March 17 10:30 am

Handle With Care

"Semi Automated DIB/PIB Loader"

Alexander Wieler - esmo AG

"Mechanical Flip Burn In (FBI) for Tire Pressure Monitoring System"

Raimondo Sessego, James Stanley, & Joe Milazzo - Freescale Semiconductor

"Final Test Solution of WLCSP devices"

Mike Frazier- Xcerra Corporation

Copyright Notice

The presentation(s)/paper(s) in this publication comprise the Proceedings of the 2015 BiTS Workshop. The content reflects the opinion of the authors and their respective companies. They are reproduced here as they were presented at the 2015 BiTS Workshop. This version of the papers may differ from the version that was distributed in hardcopy & softcopy form at the 2015 BiTS Workshop. The inclusion of the presentations/papers in this publication does not constitute an endorsement by BiTS Workshop or the workshop's sponsors.

There is NO copyright protection claimed on the presentation content by BiTS Workshop. However, each presentation is the work of the authors and their respective companies: as such, it is strongly encouraged that any use reflect proper acknowledgement to the appropriate source. Any questions regarding the use of any materials presented should be directed to the author(s) or their companies.

The BiTS logo and 'Burn-in & Test Strategies Workshop' are trademarks of BiTS Workshop. All rights reserved.

SEMI AUTOMATED DIB/ PIB LOADER

Alexander Wieler
esmo-AG



2015 BiTS Workshop
March 15 - 18, 2015

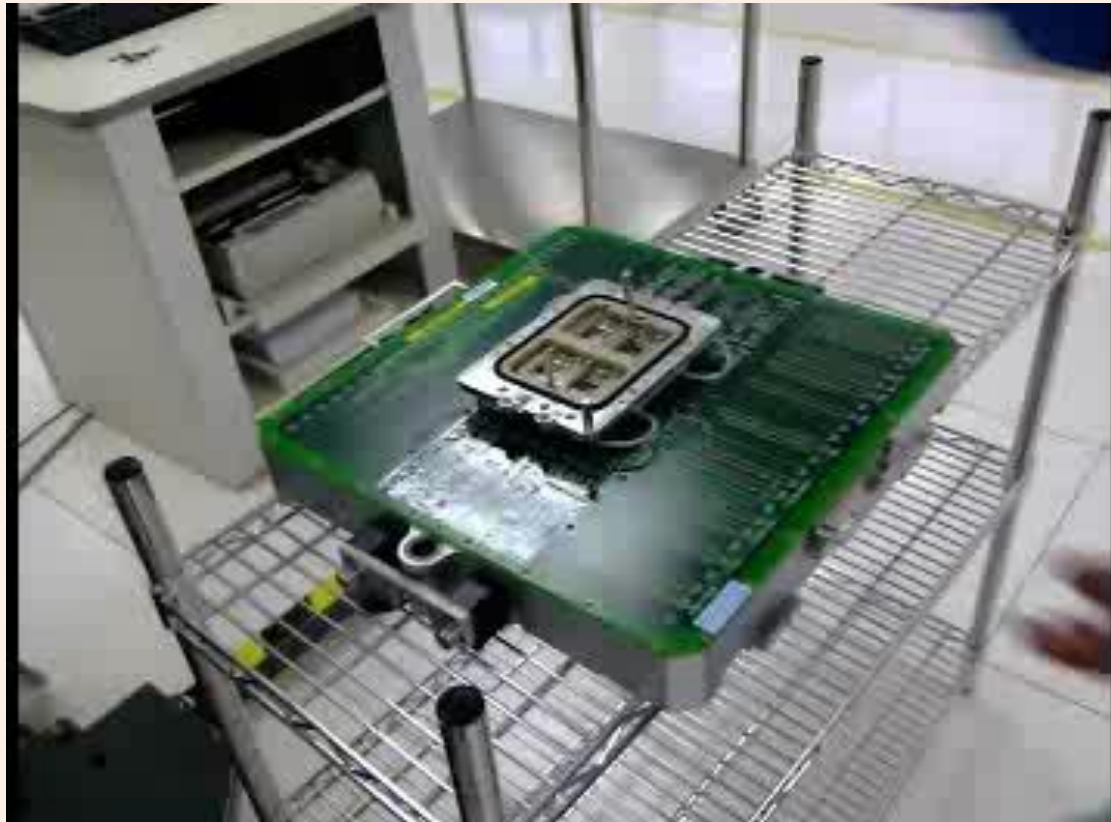


DIB Loader with Cold Test Cover

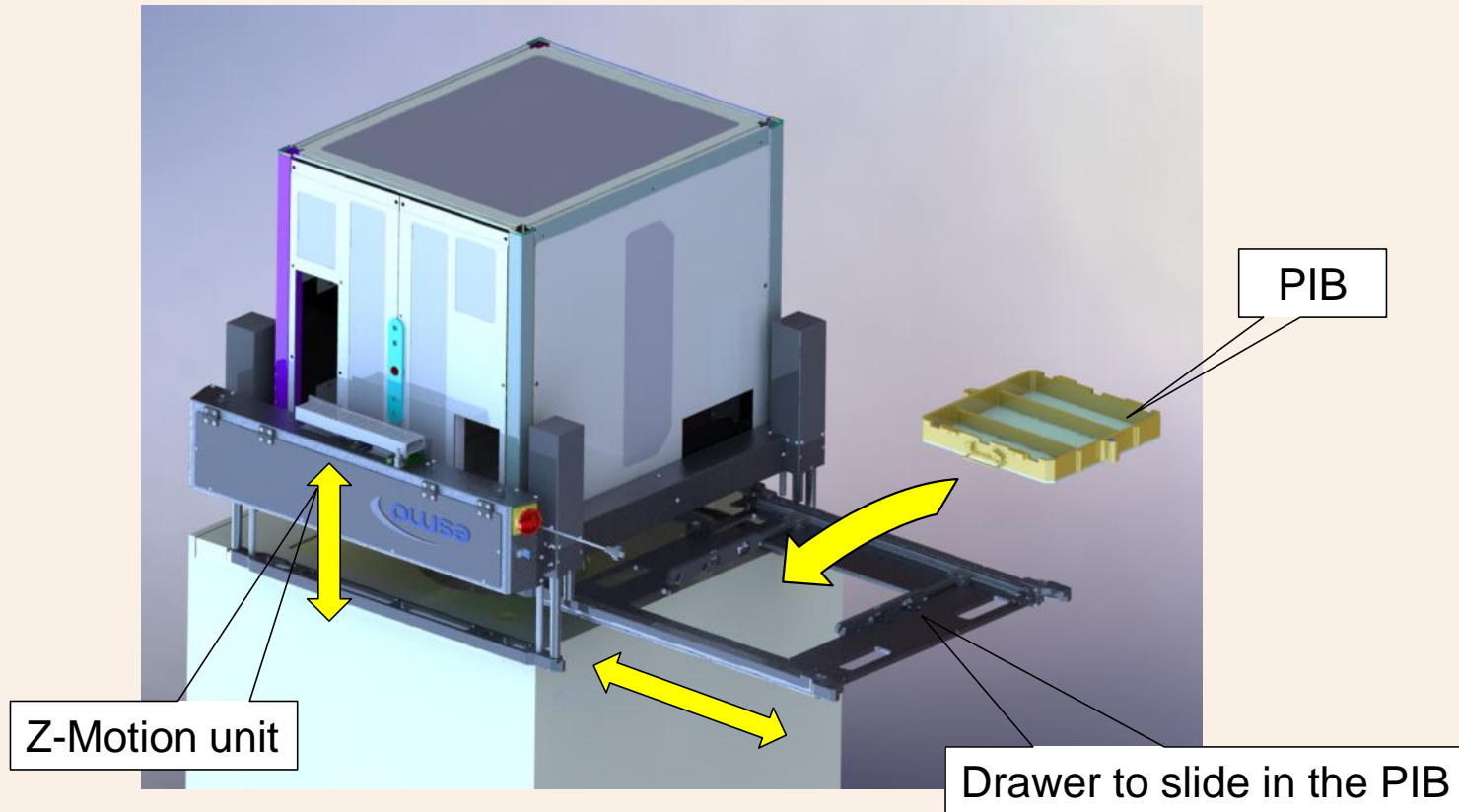


- dib-lock system allows easy and fast change of loadboards (board change within 1 minute possible)
- 100% Yield possible
- dib-lock works without any additional docking system (no K-dock required)
- up to 80% time reduction in production for Service and Board change
- dib-lock guaranties high repeatability and safe docking– undocking process

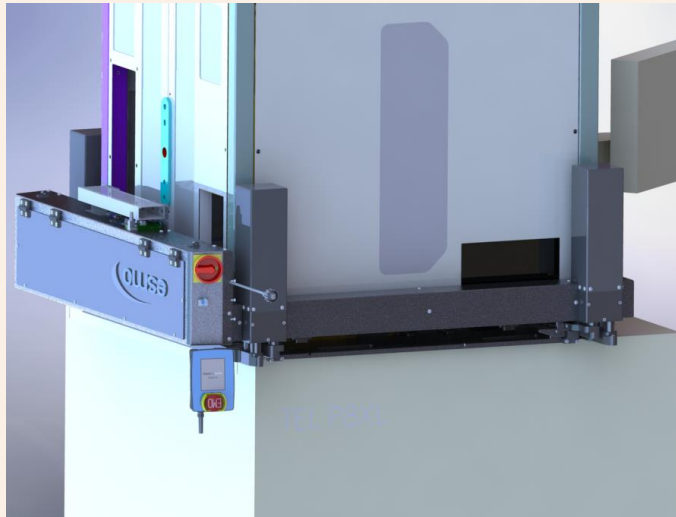
DIB Changer with Cold Test Cover



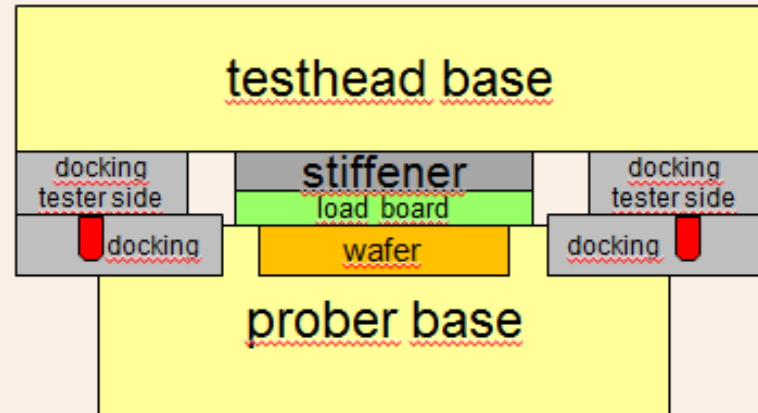
PIB Loader for Prober



PIB Loader for Prober

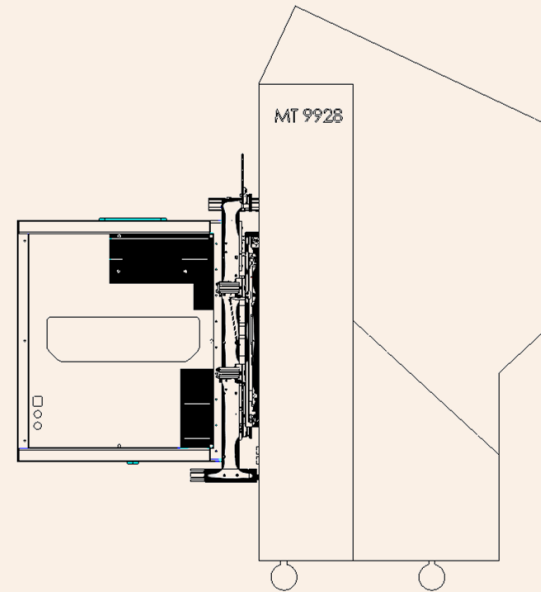
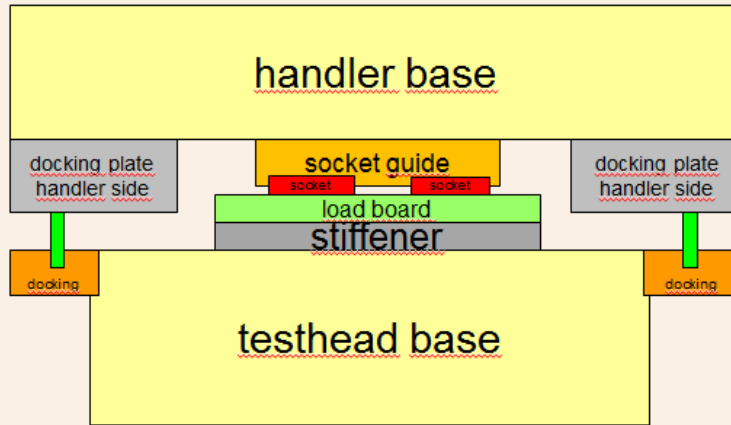


testhead docked



Semi automated DIB Loader

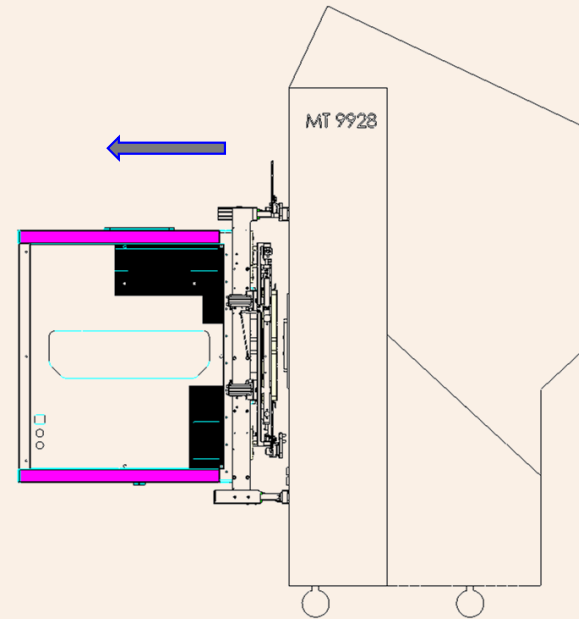
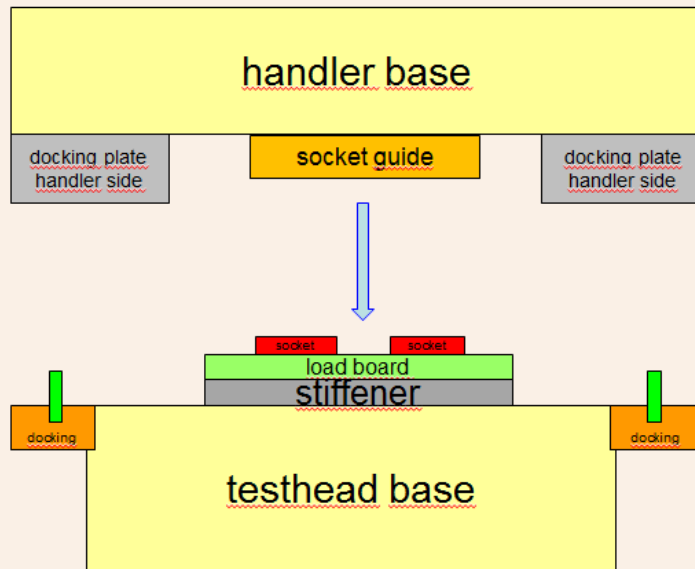
Concept Top view



Handler Side view

Semi automated DIB Loader

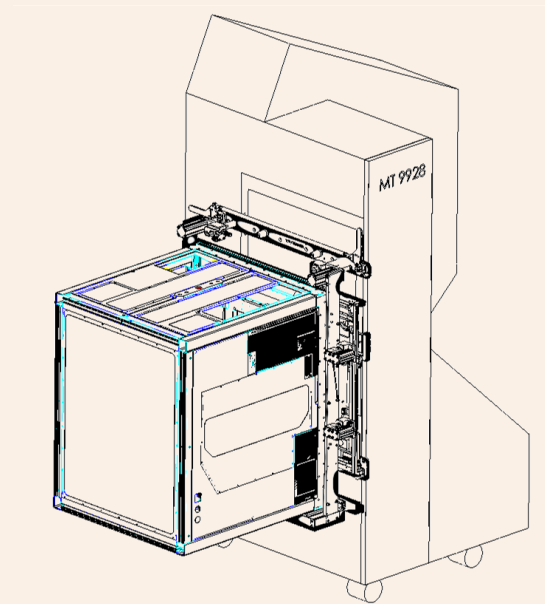
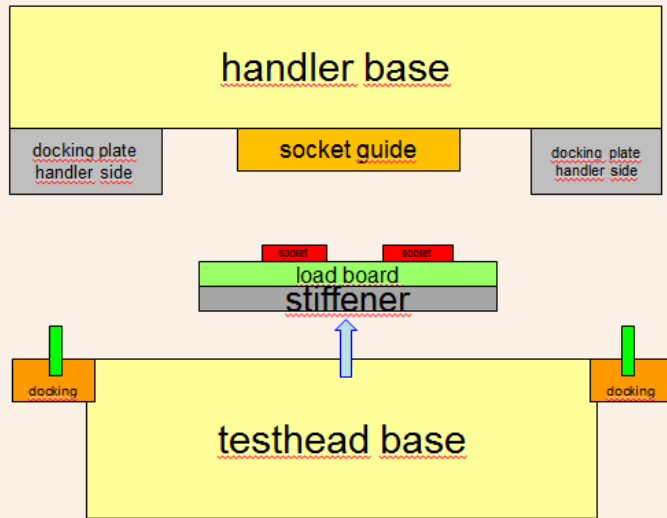
Concept Top view



Handler Side view

Semi automated DIB Loader

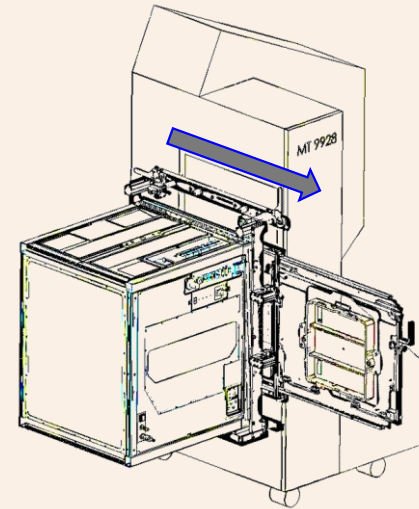
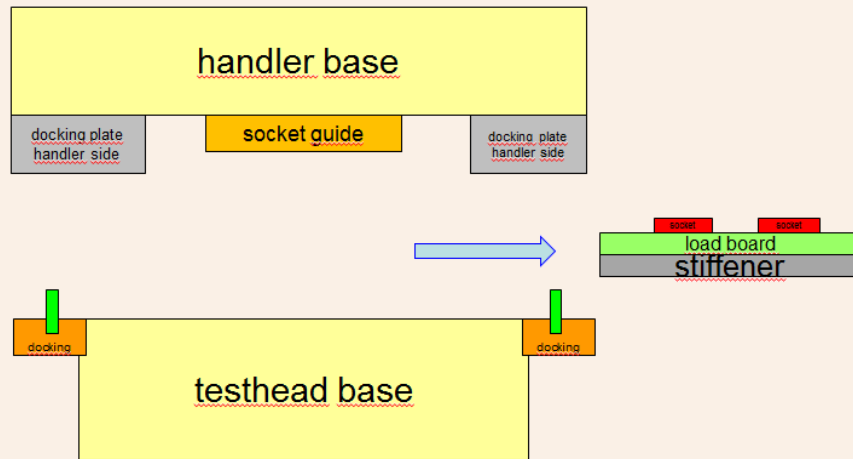
Concept Top view



Handler Side view

Semi automated DIB Loader

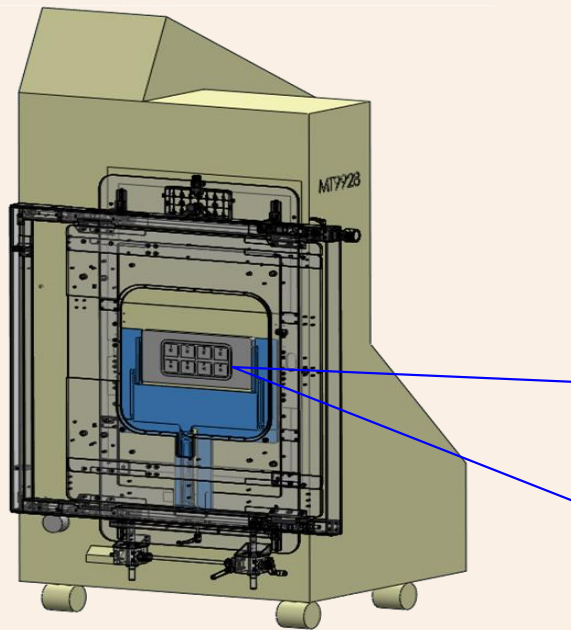
Concept Top view



Handler Side view

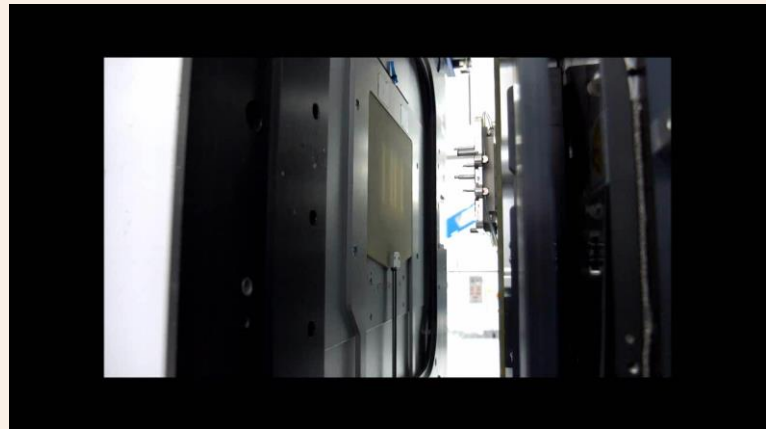
Cold Test Cover

For Cold Test: no need to bring the Handler into ambient conditions,
Cold Test Cover will close the contactors during Service

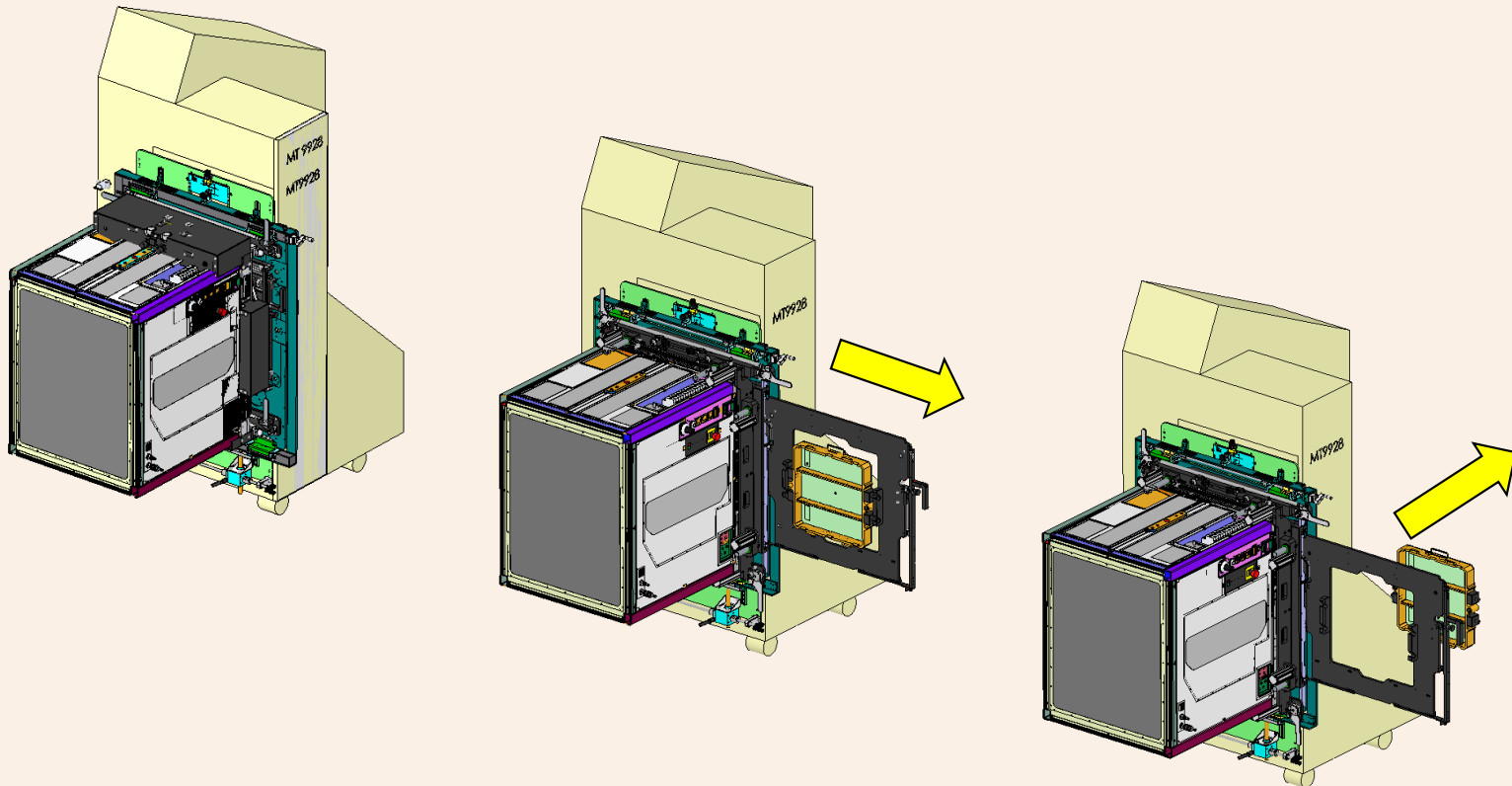


Handler rear side

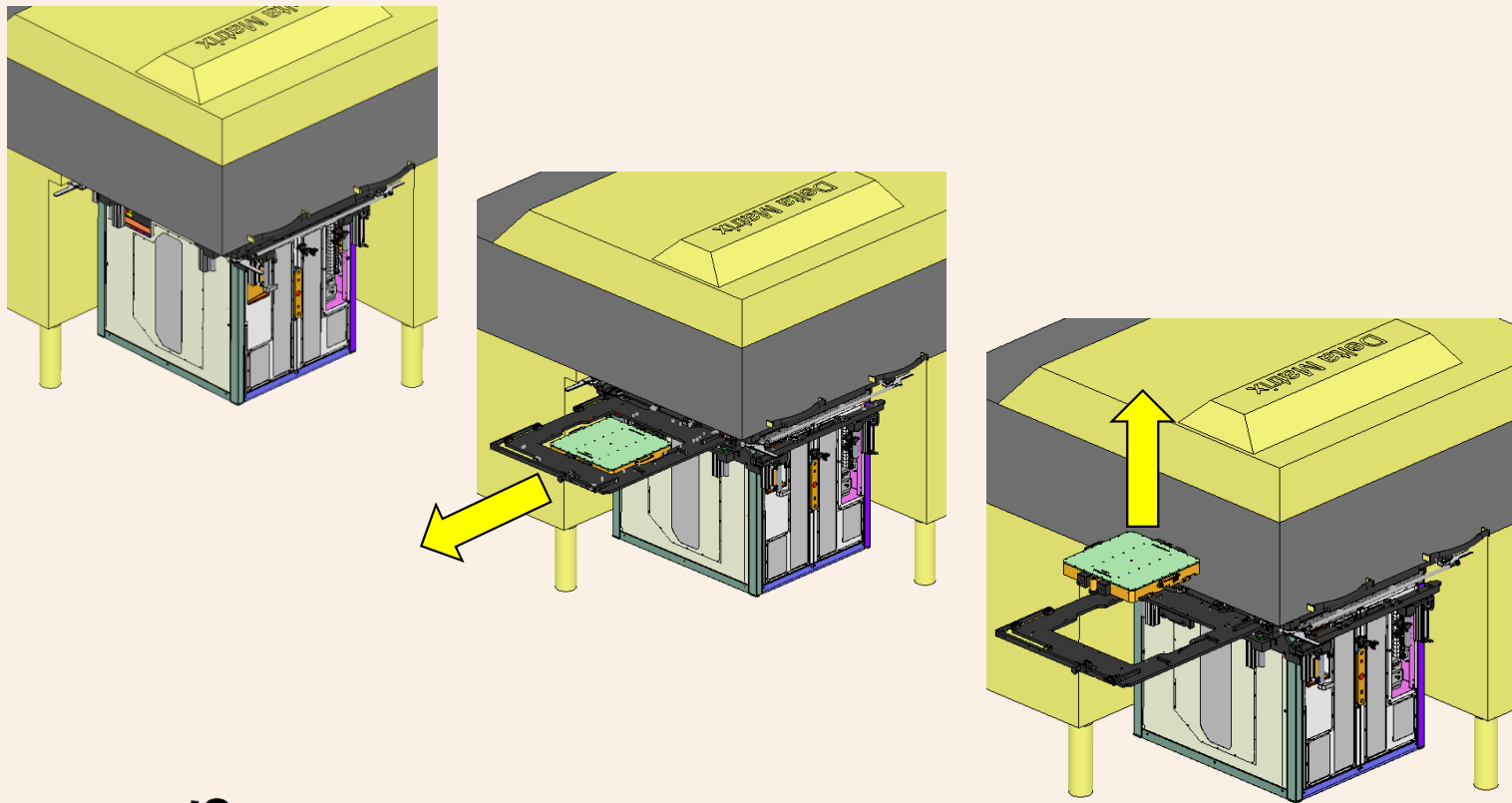
Movie



Docking of testhead to vertical plane Handler



Docking of testhead to horizontal plane Handler



Semi automated DIB Loader